

Source of systematic uncertainty	Uncertainty (%)
Muon identification efficiency (syst.)	2.1
Jet energy scale	1.8–1.9
Electron identification efficiency (syst.)	1.6
Electron identification efficiency (stat.)	1.0
Pileup	0.9–1.0
Electron trigger efficiency	0.7
τ_h veto efficiency	0.6–0.7
p_T^{miss} trigger efficiency (jets plus p_T^{miss} region)	0.7
p_T^{miss} trigger efficiency ($Z/\gamma^* \rightarrow \mu\mu$ region)	0.6
Boson p_T dependence of QCD corrections	0.5
Jet energy resolution	0.3–0.5
p_T^{miss} trigger efficiency (μ + jets region)	0.4
Muon identification efficiency (stat.)	0.3
Electron reconstruction efficiency (syst.)	0.3
Boson p_T dependence of EW corrections	0.3
PDFs	0.2
Renormalization/factorization scale	0.2
Electron reconstruction efficiency (stat.)	0.2
Overall	3.2